## **Electronic supplementary information**

## Self-Powered Broadband, High-Detectivity and Ultrafast Photodetectors Based on Pd-MoS<sub>2</sub>/Si Heterojunctions

L. Z. Hao, \*a,b W. Gao, b Y. J. Liu, b Y. M. Liu, b Z. D. Han, b Q. Z. Xue, \*a and J. Zhuc

<sup>a</sup>State Key Laboratory of Heavy Oil Processing, China University of Petroleum,

Qingdao, Shandong 266580, P. R. China

<sup>b</sup>College of Science, China University of Petroleum, Qingdao, Shandong 266580, P.

R. China

<sup>c</sup>State Key Laboratory of Electronic Thin Films and Integrated Devices, University of Electronic Science and Technology of China, Chengdu 610054, P. R. China

## **Corresponding Authors**

Email: <u>haolanzhong@upc.edu.cn</u>; <u>xueqz@upc.edu.cn</u>

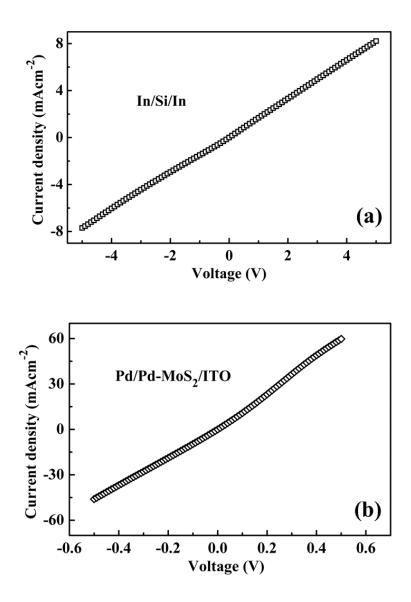
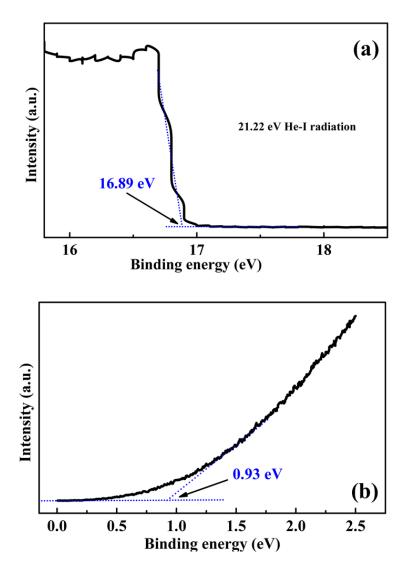


Fig. S1. *I-V* curves of (a) the In/n-Si/In and (b) thePd/Pd-MoS<sub>2</sub> film/ITO.

Fig. S1 shows the *J*-*V* curves of the In/n-Si/In and Pd/ Pd-MoS<sub>2</sub> film/ITO structure, respectively. From the figure, the linear characteristics of the J-V curves for both the devices are observed. This demonstrates that the contacts of In/Si and Pd/Pd-MoS<sub>2</sub> film are ohmic.



**Fig. S2.** UPS spectra of the MoS<sub>2</sub> film on Si, showing its Fermi level (a) and the distance between the Fermi level and the conduction band (b), respectively.

Figure S2 shows the UPS spectrum of the MoS<sub>2</sub> film without Pd doping. The work function (*W*) of the film can be calculated from the difference between the cutoff of the highest binding energy and the photon energy of the exciting radiation. As shown in Figure S2(a), W=4.33 eV. The distance ( $\Delta E$ ) between the valence band and Fermi level of MoS<sub>2</sub> film can be extracted from the onset energy, as shown in Figure 2S(b). The  $\Delta E$  is determined to be 0.93 eV. This further demonstrates the n-type behavior of the MoS<sub>2</sub> film without Pd doping.